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Detailed reliability data organized by manufacturer and device technology, including:

- Beckman Instruments
- Centralab
- Circuit Technology Inc.
- Collins Radio Company

- Crystalonics
- CTS Microelectronics
- Dale Electronics
- DuPont Electric Products
- Fairchild Semiconductor
- Hewlett-Packard
- Hughes Aircraft Company
- Intersil
- Lockheed Electronics
- Motorola Semiconductor
- National Semiconductor
- Raytheon Corporation
- Sprague Electric
- Texas Instruments
- TRW Electronics
- and many others

Technologies covered include:

- Thick-film digital circuits
- Thick-film linear circuits
- Thin-film digital circuits
- Thin-film linear circuits
- Semiconductor digital circuits
- Semiconductor linear circuits

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